

L Number	Hits	Search Text	DB	Time stamp
1	0	(156/345.13).CCLS.	JPO; DERWENT	2003/05/29 14:22
2	51	(156/345.13).CCLS.	USPAT	2003/05/29 14:33
3	0	(156/345.12 156/345.31 156/345.32 451/66).CCLS.	USPAT	2003/05/29 14:34
4	441	((156/345.12 ) or (156/345.31 ) or (156/345.32 ) or (451/66)).CCLS.	USPAT	2003/05/29 14:34
5	437	((((156/345.12 ) or (156/345.31 ) or (156/345.32 ) or (451/66)).CCLS.) not ((156/345.13).CCLS.))	USPAT	2003/05/29 14:48
6	165	"5655954" "5337015" "5948203"	USPAT	2003/05/29 14:58
7	6747	kimura-\$ .in. koitama-\$ .in. akagi-\$ .in.	USPAT	2003/05/29 14:59
8	390	(kimura-\$ .in. koitama-\$ .in. akagi-\$ .in.) and (polish\$3 planariz\$5 abrad\$3)	USPAT	2003/05/29 14:59
9	386	((kimura-\$ .in. koitama-\$ .in. akagi-\$ .in.) and (polish\$3 planariz\$5 abrad\$3)) not (((156/345.13).CCLS.) (((156/345.12 ) or (156/345.31 ) or (451/66)).CCLS.) (((((156/345.12 ) or (156/345.31 ) or (451/66)).CCLS.) not ((156/345.13).CCLS.)))	USPAT	2003/05/29 15:01
10	234	(((kimura-\$ .in. koitama-\$ .in. akagi-\$ .in.) and (polish\$3 planariz\$5 abrad\$3)) not (((156/345.13).CCLS.) (((156/345.12 ) or (156/345.31 ) or (451/66)).CCLS.) (((((156/345.12 ) or (156/345.31 ) or (451/66)).CCLS.) not ((156/345.13).CCLS.)))) and (atomiz\$5 control\$3)	USPAT	2003/05/29 15:02
11	116	((((kimura-\$ .in. koitama-\$ .in. akagi-\$ .in.) and (polish\$3 planariz\$5 abrad\$3)) not (((156/345.13).CCLS.) (((156/345.12 ) or (156/345.31 ) or (451/66)).CCLS.) (((((156/345.12 ) or (156/345.31 ) or (156/345.32 ) or (451/66)).CCLS.) not ((156/345.13).CCLS.)))) and (atomiz\$5 control\$3)) and (wafer semiconductor)	USPAT	2003/05/29 15:02
-	114	(156/345.12,156/345.31, 156/345.32).ccls.	USPAT	2003/03/12 13:19
-	1667	438/692.ccls. 414/(271,940,941,938).ccls. 451/66 216/88	USPAT	2002/10/22 12:28
-	1708	((156/345.12,156/345.31, 156/345.32).ccls.) (438/692.cccls. 414/(271,940,941,938).ccls. 451/66 216/88)	USPAT	2002/12/28 09:48
-	194	((((156/345.12,156/345.31, 156/345.32).ccls.) (438/692.cccls. 414/(271,940,941,938).ccls. 451/66 216/88)) and ((thickness depth metrology) same (clean\$3 buff\$3 wash\$3 rins\$3)))	USPAT	2002/10/22 12:30
-	408	((((156/345.12,156/345.31, 156/345.32).ccls.) (438/692.cccls. 414/(271,940,941,938).ccls. 451/66 216/88)) and (multiple plural\$3) with (polish\$3 clean\$3))	USPAT	2002/10/22 12:34
-	59	((((156/345.12,156/345.31, 156/345.32).ccls.) (438/692.cccls. 414/(271,940,941,938).ccls. 451/66 216/88)) and ((thickness depth metrology) same (clean\$3 buff\$3 wash\$3 rins\$3))) and (((((156/345.12,156/345.31, 156/345.32).ccls.) (438/692.cccls. 414/(271,940,941,938).ccls. 451/66 216/88)) and (multiple plural\$3) with (polish\$3 clean\$3)))	USPAT	2002/10/22 12:31

-	211	((((156/345.12,156/345.31, 156/345.32).ccls.) (438/692.cccls. 414/(271,940,941,938).cccls. 451/66 216/88)) and ((thickness depth metrology) same (clean\$3 buff\$3 wash\$3 rins\$3))) (((156/345.12,156/345.31, 156/345.32).ccls.) (438/692.cccls. 414/(271,940,941,938).cccls. 451/66 216/88)) and (multiple plural\$3) with (polish\$3 clean\$3)) and (elevator cassette vertical\$2) ( (((156/345.12,156/345.31, 156/345.32).ccls.) (438/692.cccls. 414/(271,940,941,938).cccls. 451/66 216/88)) and ((thickness depth metrology) same (clean\$3 buff\$3 wash\$3 rins\$3)).and (((156/345.12,156/345.31, 156/345.32).ccls.) (438/692.cccls. 414/(271,940,941,938).cccls. 451/66 216/88)) and (multiple plural\$3) with (polish\$3 clean\$3)) and (elevator cassette vertical\$2)	USPAT	2002/10/22 12:32
-	31	((((156/345.12,156/345.31, 156/345.32).ccls.) (438/692.cccls. 414/(271,940,941,938).cccls. 451/66 216/88)) and ((thickness depth metrology) same (clean\$3 buff\$3 wash\$3 rins\$3)).and (((156/345.12,156/345.31, 156/345.32).ccls.) (438/692.cccls. 414/(271,940,941,938).cccls. 451/66 216/88)) and (multiple plural\$3) with (polish\$3 clean\$3)) and (elevator cassette vertical\$2)	USPAT	2002/10/22 12:33
-	38	((156/345.12,156/345.31, 156/345.32).ccls.) (438/692.cccls. 414/(271,940,941,938).cccls. 451/66 216/88)) and (multiple plural\$3) with (polish\$3 and clean\$3)	USPAT	2002/10/22 12:44
-	9770	(planariz\$5 polish\$3) same (clean\$3 rins\$3 wash\$3)	EPO; JPO; DERWENT	2002/10/22 12:53
-	1815	((planariz\$5 polish\$3) same (clean\$3 rins\$3 wash\$3)) and (semiconductor wafer)	EPO; JPO; DERWENT	2002/10/22 12:55
-	73	((planariz\$5 polish\$3) same (clean\$3 rins\$3 wash\$3)) and (semiconductor wafer)) and (thickness metrology depth width) with (clean\$3 rins\$3 wash\$3)	EPO; JPO; DERWENT	2002/10/22 12:55
-	7	((("6213853") or ("6036582") or ("6050884") or ("6110024") or ("6168683") or ("5830045") or ("5827110")).PN. (("2001257248") or ("81744417")).PN.	USPAT	2002/10/31 11:23
-	2	((("2001257248") or ("81744417")).PN.	JPO; DERWENT	2003/05/29 14:22
-	1774	((156/345.12,156/345.31, 156/345.32).ccls.) (438/692.cccls. 414/(271,940,941,938).cccls. 451/66 216/88)	USPAT	2002/12/28 09:48
-	1356	((156/345.12,156/345.31, 156/345.32).ccls.) (438/692.cccls. 414/(271,940,941,938).cccls. 451/66 216/88) ) and (metrology thickness measur\$3)	USPAT	2002/12/28 10:02
-	510	((((156/345.12,156/345.31, 156/345.32).ccls.) (438/692.cccls. 414/(271,940,941,938).cccls. 451/66 216/88) ) and (metrology thickness measur\$3)) and (clean\$3 polish\$3) near5 (metrology thickness measur\$3)	USPAT	2002/12/28 10:01
-	0	156/345.13,156/345.16,156/345.15,cccls.	USPAT	2002/12/28 10:01
-	145	156/345.13 156/345.16 156/345.15	USPAT	2002/12/28 10:02
-	95	(156/345.13 156/345.16 156/345.15) and (metrology thickness measur\$3)	USPAT	2002/12/28 10:02
-	158	"5655954" "5337015" "5948203"	USPAT	2003/03/12 13:19
-	3	("5655954" "5337015" "5948203").pn.	USPAT	2003/03/12 13:19